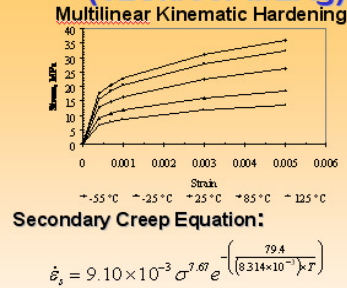
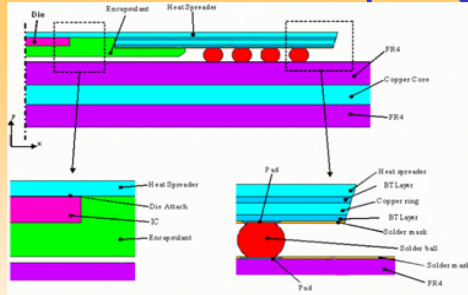
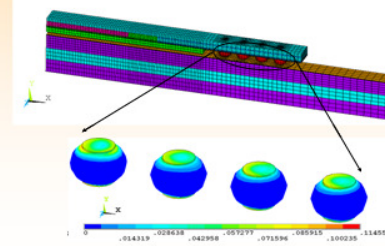
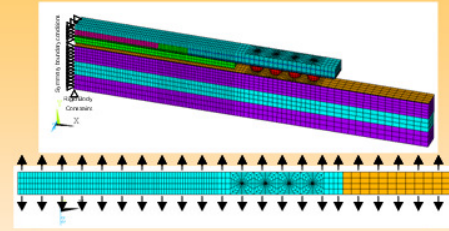


# Reliability Assessment of a PBGA package

## Schematic of an SBGA package Solder Material Modeling (62Sn/36Pb/2Ag)



## Results From Numerical Simulation

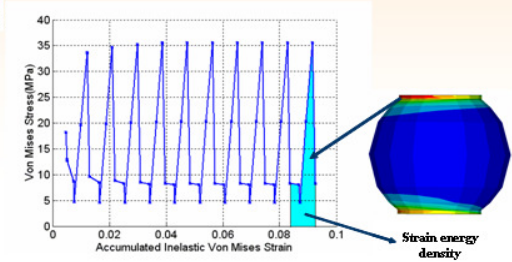


Accumulated inelastic strain energy density contours for the SBGA 352 package

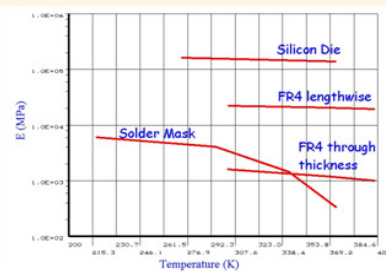
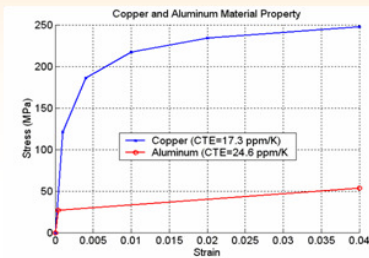
Number of cycles to failure =  $N_f$   
 Number of cycles for crack initiation =  $N_o$   
 Number of cycles for crack Propagation =  $N_p$   
 Diameter of the solder ball along the copper pad =  $a$

$$N_o = C_3 \Delta W_{ave}^{C_4}$$

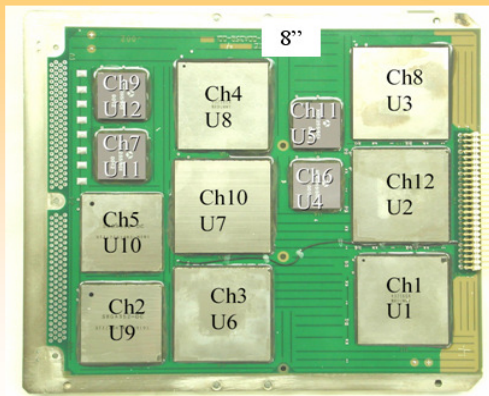
$$N_p = \frac{a}{da/dN} \text{ where } \frac{da}{dN} = C_5 \Delta W_{ave}^{C_6}$$

$$N_f = N_o + N_p$$


## Silicon, Metal, and Polymer Models



## Test Vehicle Description

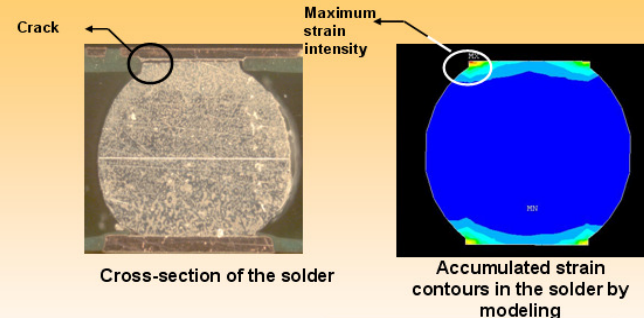


Locator	Type	Package size, mm
U1	432 SBGA	40X40
U2	560 SBGA	42.5X42.5
U3	560 SBGA	42.5X42.5
U4	255 CI-CGA	21X21
U5	255 CI-CGA	21X21
U6	560 SBGA	42.5X42.5
U7	560 SBGA	42.5X42.5
U8	432 SBGA	40X40
U9	352 SBGA	35X35
U10	352 SBGA	35X35
U11	255 CI-CGA	21X21
U12	255 CI-CGA	21X21

- Intended to be used in Military Applications
- Underfilled to prevent moisture condensation
- Subjected to MIL-STD 883E condition B temperatures; -55 °C to 125 °C

- SBGA - AMKOR
- CI-CGA - Thomson-CSF

## FE Validation



The location of the observed crack in the outermost solder ball after the ATC matches well with the predicted location

Predicted Results (N50 %)	Experimental Data (ITRI) (N50 %)	Experimental Data (GT) (N50 %)
3630 cycles	3300 cycles	3462 cycles

